



<b>Searched</b>  	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10511475	TSUDA ET AL.
	Examiner Han, Jason M	Art Unit 2875

Class	SubClass	Date	Examiner
362	19, 330, 600, 606-610, 615-619, 623, 626	6/2/2006	JMH
349	61-65, 68-69	6/2/2006	JMH

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